WHAT IS CLAIMED IS:

- 1. A method for growing a plurality of carbon nanotubes on a selective area, comprising steps of:
 - a) forming a first masking layer on a first substrate;
- b) photolithographing said first masking layer for forming a plurality of specific areas on said first substrate;
- c) etching said plurality of specific areas for forming a second masking layer on said first substrate;
- d) etching said second masking layer and said first substrate for forming a plurality of tapered structures;
 - e) applying a catalyst on said plurality of tapered structures;
- f) imprinting a second substrate on said first substrate having said catalyst thereon for being a growth substrate with a plurality of vestiges of said catalyst; and
 - g) growing said plurality of carbon nanotubes on said growth substrate.
- 2. The method as claimed in claim 1, wherein both said first substrate and said second substrate are silicon substrates.
- 3. The method as claimed in claim 1, wherein said first masking layer is a first silicon oxide masking layer formed at a temperature ranged from 800 to 1200 ℃ and has a thickness ranged from 2000 to 7000 Å.
- 4. The method as claimed in claim 1, wherein said step c) is performed by a BOE (Buffer Oxide Etching) solution containing a hydrofluoric acid.
- 5. The method as claimed in claim 1, wherein said step d) is performed by a chemical solution containing a potassium hydroxide.
- 6. The method as claimed in claim 1, wherein said step e) is performed by a physical deposition method.

- 7. The method as claimed in claim 1, wherein said second masking layer is formed just on said plurality of specific areas.
- 8. The method as claimed in claim 1, wherein said plurality of tapered structures are a plurality of sharp silicon structures.
- 9. The method as claimed in claim 1, wherein said step b) further comprises steps of:
 - b1) providing a mask;
 - b2) forming a first photoresist layer on said first masking layer; and
- b3) etching said first photoresist layer with said mask for forming a second photoresist layer.
- 10. The method as claimed in claim 9, wherein said second masking layer comprises said second photoresist layer and a second silicon oxide masking layer.
- 11. The method as claimed in claim 10, wherein said step c) further comprises a step of c1) removing said second photoresist layer by an acetone.
- 12. The method as claimed in claim 1, wherein said catalyst is a metal catalyst selected from a group consisting of a ferrum, a cobalt, and a nickel.
- 13. The method as claimed in claim 1, wherein each of said plurality of vestiges of said catalyst has a diameter ranged from 10 to 200 nanometers.
- 14. The method as claimed in claim 13, wherein each of said plurality of vestiges of said catalyst introduces a growth of each of said carbon nanotubes.
- 15. A method for growing a plurality of carbon nanotubes on a selective area, comprising steps of:
 - a) forming a first masking layer on a first substrate;
- b) photolithographing said first masking layer for forming a plurality of specific areas on said first substrate;

- c) etching said plurality of specific areas for forming a second masking layer on said first substrate;
- d) etching said second masking layer and said first substrate for forming a plurality of tapered structures on said first substrate;
 - e) applying a catalyst on a second substrate;
- f) imprinting said first substrate on said second substrate for respectively obtaining a residuum on a tip of each of said plurality of tapered structures; and
- g) respectively growing each of said carbon nanotubes on each of said plurality of tapered structures having said residuum.
- 16. The method as claimed in claim 15, wherein said catalyst is a metal catalyst selected from a group consisting of a ferrum, a cobalt, and a nickel.
- 17. The method as claimed in claim 15, wherein said step b) further comprises steps of:
 - b1) providing a mask;
 - b2) forming a first photoresist layer on said first masking layer; and
- b3) etching said first photoresist layer with said mask for forming a second photoresist layer.
- 18. A method for growing a plurality of carbon nanotubes, comprising steps of:
 - a) providing a first substrate having a plurality of tapered structures;
 - b) applying a catalyst on said plurality of tapered structures;
- c) imprinting a second substrate on said first substrate for obtaining a plurality of vestiges of said catalyst on said second substrate; and
 - d) growing said plurality of carbon nanotubes on said plurality of vestiges.
- 19. The method as claimed in claim 18, wherein said catalyst is a metal catalyst selected from a group consisting of a ferrum, a cobalt, and a nickel.

- 20. A carbon nanotube structure, comprising:
 - a silicon substrate;
 - at least an imprinted vestige deposited on said silicon substrate; and at least a carbon nanotube grown on said imprinted vestige.
- 21. The structure as claimed in claim 20, wherein said imprinted vestige is formed by a metal imprint technique.
- 22. A carbon nanotube structure, comprising:
 - a silicon substrate with a plurality of tapered structures; and
- a plurality of carbon nanotubes respectively grown on a tip of each of said plurality of tapered structures.
- 23. The structure as claimed in claim 22, wherein said plurality of carbon nanotubes are grown along a same direction.
- 24. The structure as claimed in claim 22, wherein said plurality of tapered structures are formed by steps of a photolithography, a first etching, and a second etching.
- 25. The structure as claimed in claim 22, wherein said plurality of carbon nanotubes are introduced to grow by a metal catalyst.